SON-1782/ROI

PATENT APPLICATION

1763

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit:

Ex'r:

In the Patent Application of

Hideo YAMANAKA et al.

Serial No. 09/646,680

Filed: September 20, 2000

FILM FORMING METHOD AND FILM

NORMING APPARATUS

Parviz Hassanzadeh

PECENEL 12002 TO 12002

RESPONSE ELECTING INVENTION

Commissioner for Patents Washington, D.C. 20231

Sir:

In response to the Official Action dated December 21, 2001 (Paper No. 5), please amend the above-identified application as follows:

## IN THE SPECIFICATION:

Please rewrite the following paragraphs as set forth below in clean form. Additionally, in accordance with 37 CFR 1.121(b)(1)(iii), the amended paragraphs are set forth in a marked-up version in the pages attached to this Amendment.

## Beginning at page 2, line 7,

(1) Lack of uniformity and fluctuation of a plasma field, and a non-uniform electric field in plasma-induced electric charges are generated. These may cause damages and short circuits t the transistor (e.g., charge-up or discharge breakdown of a gate oxide film, discharge between wirings, and the like).

